



Deep Learning in Object Detection and Tracking (2nd Edition)

Guest Editor:

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Message from the Guest Editor

Object detection, as one of the most fundamental and challenging problems in computer vision, has received great attention in recent years. Its development in the past two decades can be regarded as the epitome of computer vision history. As one of the fundamental problems of computer vision, object detection forms the basis of many other computer vision tasks, such as instance segmentation, image captioning, object tracking, etc. In recent years, the rapid development of deep learning techniques has brought new opportunities into the field of object detection, leading to remarkable breakthroughs and pushing it forward to a research hotspot with unprecedented attention.

In this Special Issue, original research articles and reviews are welcome. Research areas may include (but are not limited to) the following:

- Object detection and tracking;
- Few-shots/zero-shot object detection and tracking;
- Weak/semi/unsupervised object detection and tracking;
- Long-tailed object detection and tracking;
- Small object detection;
- Rotated object detection.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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